

**Search Notes**

Application/Control No.

10/644,794

Examiner

Emily Y. Chan

Applicant(s)/Patent under  
Reexamination

NOJIRI ET AL.

Art Unit

2829

**SEARCHED**

| Class | Subclass | Date     | Examiner |
|-------|----------|----------|----------|
| 324   | 770      | 5/9/2005 | EC       |
| 324   | 770      | 8/4/2005 | EC       |
| above | updated  | 8/4/2005 | EC       |
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**INTERFERENCE SEARCHED**

| Class  | Subclass | Date     | Examiner |
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| PG PUB | searchd  | 8/4/2005 | EC       |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|   | DATE     | EXMR |
|---|----------|------|
| Inventorship and EAST for all databases searched. | 5/9/2005 | EC   |
| Consulted with primary examiner Vinh P Nguyen.    | 5/9/2005 | EC   |
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